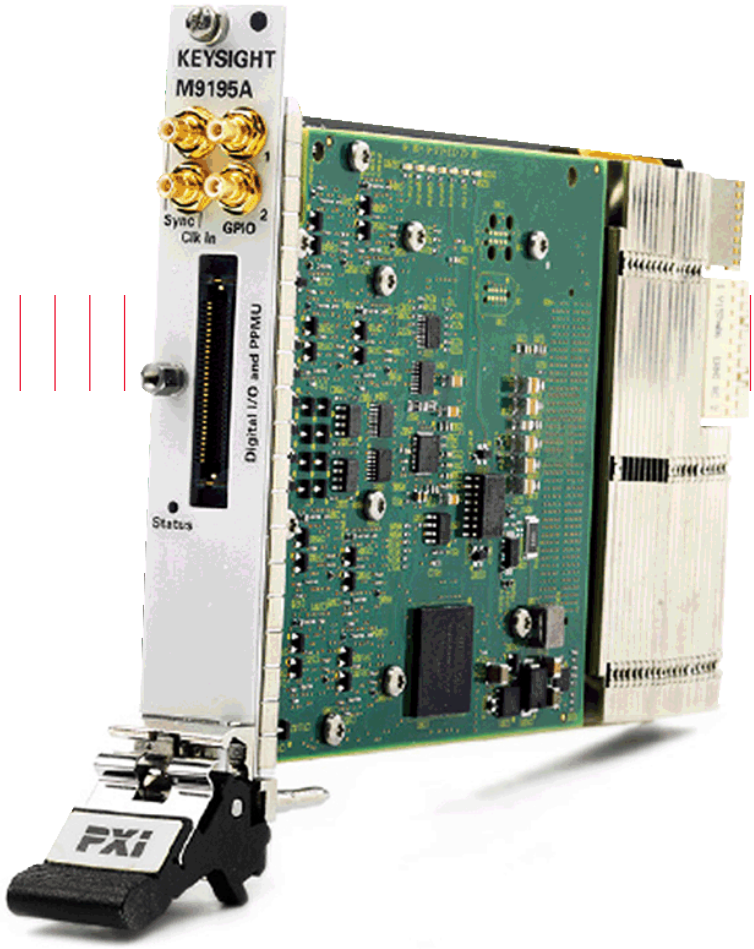
Keysight Technologies

M9195A PXIe Digital Stimulus/Response with PMU: 250 MHz, 16-channel

Data Sheet

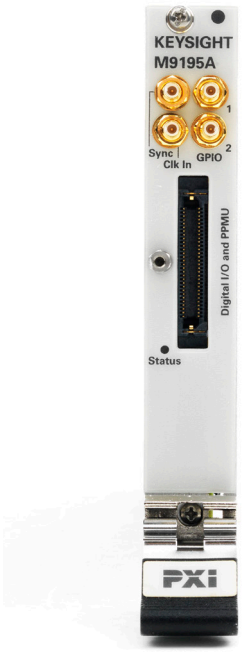


KEYSIGHT TECHNOLOGIES

Unlocking Measurement Insights

Overview

Experience high speed digital test capabilities at a whole new level. The Keysight Technologies, Inc. M9195A PXIe Digital Stimulus/Response (PXI DSR) module is ideal for IC design validation and production test environments. It goes beyond providing just standard capabilities. The new 16-channel, single slot PXI module introduces a high performance pattern cyclizer for powerful pattern creation including advanced timing capabilities such as multiple drive edges per cycle. This provides flexible edge placement and stimulus/response delays for timing margin testing or cable length compensation. Additionally, it can support up to four independent multi-sites with an independent sequencer for each site. Software tools included with the M9195A allow the user to modify vector and pattern parameters without requiring the user to recompile and download tests.



Additonal ATE features include:

- High speed pattern application and RZ (Return-to-Zero) clock rate up to 250 MHz
- Per pin programming of voltage levels
- Real time compare, parametric measurement unit (PMU)
- Deep vector memory and flexible pattern sequencing

With the PXI DSR module you can easily emulate standard serial interfaces like the MIPI™ RF Front-End interface or proprietary parallel device interfaces. The test development software tools enable you to quickly create and edit waveform patterns or to import patterns created by automatic test generation applications.

Applications

- RFFE bus emulation used in PA/FEM semiconductor device verification or production test
- Wireless communication devices using parallel or serial digital control
- Automated test in product validation or manufacturing test
- Backplane emulation for device, board, or module testing
- Digital serial and parallel applications

Key features

- 16 bidirectional channels with per-pin programmable logic levels
- Highly flexible, per-bit timing control for fast and accurate waveform development
- Reconfigurable per-pin Parametric Measurement Unit (PMU) for each channel
- Single and multi-site configurations
- Edit patterns on-the-fly without recompiling and downloading the test
- Execute patterns in arbitrary order
- Flexible allocation of deep pattern memory per channel or per site to allocate memory where it is needed
- Channel delay adjustment to compensate for cable and fixture propagation delays
- 4 high voltage channels for flash programming or fuse test
- 4 open drain auxillary output pins for fixture relays
- Comprehensive software tool set for quick test development

M9195A hardware overview

Individual channel capability

Each of the 16 bidirectional channels provide programmable logic levels of -1.5 V to +6.5 V with 152 µV resolution. The per channel 4 quadrant parametric measurement unit (PMU) enables FVMI, FIMV, FVMV, and FIMI and FNMV modes. With the 5 PMU current ranges between ±2 µA to ±40 mA, users can make accurate leakage measurements.

Each channel can be configured for parametric measurements, as a static digital I/O pin, or with synchronized cyclized digital data. Digital channel direction and timing can be flexibly controlled on a per digital vector basis. The cyclized data allows each pin to operate in RZ or NRZ modes. In combination with the 1 ns edge placement resolution, each pin allows for an adjustable output delay, for timing margin testing, and receive delay to compensate for cabling propagation delays.

Multi-site capability

The PXI DSR provides a choice of a single-site configuration with 16 synchronized channels, or a multi-site configuration with 4 sets of 4 synchronized channels. In multi-site mode, each site has its own independent sequencer. This enables site independent clock operation for simultaneous testing. The multi-site capability simplifies test development. Instead of forcing the test engineer to create a single test that encompasses all for sites simultaneously, the user only needs to focus on a single device. The single device test can be easily replicated for the remaining test sites. In addition to the digital pins, each site has a high voltage drive channel and an open drain control channel for relay control.

Parametric Measurement Unit (PMU)

The PMU feature, available on each of the PXI DSR's 16 channels, enables DC current and voltage measurements. The PMUs can be independently programmed to force a voltage and measure the corresponding current, or force a current and measure the voltage. The PMU can make leakage current measurements at low current ranges or for measuring low input resistance in high current ranges. In a force voltage/measure current (FVMI) mode the PMU can measure input bias current on a single DUT pin. For high current applications, each channel has remote sense capability to account for the voltage drop across the connecting cable.

Perform continuity testing of a DUT by forcing current into the pin with other DUT pins grounded while measuring the voltage at the pin (FIMV). The FNMV mode (Force Nothing, Measure Voltage) enables the PMU to be used as a scanning voltmeter. The PMU provides built-in 64 sample, 50 Hz or 60 Hz averaging to improve measurement quality by rejecting power line noise. The PMUs share a 16-bit measurement subsystem for fast accurate measurements.

Flexible digital pattern generation

With the included software tools, easily create, modify and reuse previously defined patterns. Pattern timing is controlled using up to 32 waveform tables. Within the waveform table, each of the 15 user-defined vector characters is translated into one of the following hardware actions: Force High/Low (U/D), Force to previous state (P), Stop Forcing (Z), Compare High/Low (H/L), Compare to Tri-state (T), Don't Compare (X). Each vector period has two drive edges that are used when forcing a digital state and one receive edge used to compare digital data from the DUT. Edge placement resolution can be set as low as 1 ns and edge placement can vary from period to period so that oversampling is not required. The two drive edges enable the user to easily create a clock or other RZ formats from a single vector without requiring two vectors. The flexibility of the drive edges allow them to be changed on a per vector basis using the vector characters or by referencing a different waveform table.

The combination of the waveform tables and edge placement resolution simplifies the pattern programming. Variables and equations can be defined to allow the user to simultaneously modify timing relationships and edge placement.

Once compiled, the digital patterns are stored in the PXI DSR's on-board pattern cache. The PXI DSR executes the patterns from the cache in order to provide high test throughput. High-level pattern sequencing commands allow for high level macros which can be used to define timing sets, counted and uncounted looping of pattern blocks, conditional execution based upon matching parallel or serial patterns, or wait for software trigger advance.

Advance timing capabilities

Change pattern values that have been downloaded to the cache without recompiling. Pattern values can replace either parallel vectors or serial patterns. These powerful features allow you to quickly modify patterns directly from the API. The user can create pattern templates that are used to read or write to the DUT, then provide the vector information directly from the API.

Variables can be modified at the API level without recompiling the test pattern. This allows the user to control pattern timing or levels directly from the API. These advanced capabilities useful for test applications such as a timing or voltage level shmoo.

Serial and parallel digital bus emulation

The combination of the flexible pattern timing and sequencing features, enables the PXI DSR to emulate a wide variety of standard or custom serial/parallel protocols such as SPI and RFFE.

Comprehensive software tool set

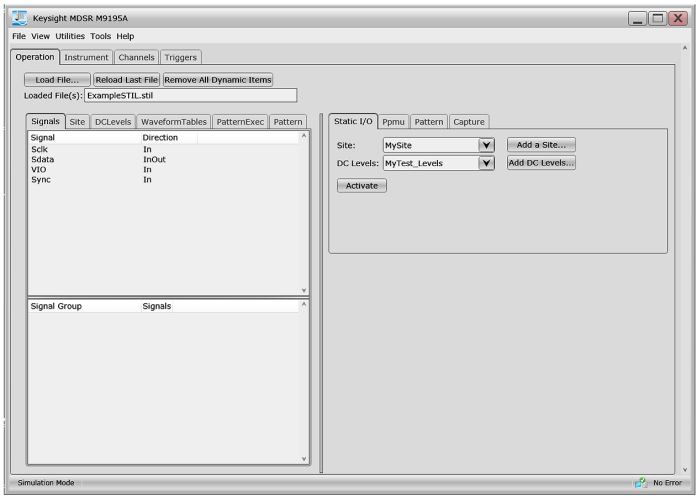
Keysight offers a choice of drivers and programming environments to configure and control the PXI DSR during test development including:

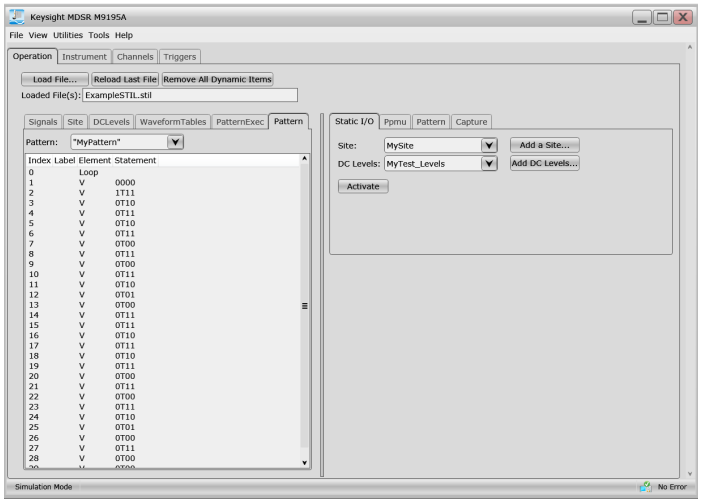
- Full featured, high-level IVI-COM, IVI-C, LabVIEW programming interfaces through drivers
- IEEE-1450/ STIL, OpenXML (Excel), or text file format for programmatically defining patterns
- The M9195A Soft Front Panel for interactive test control and debug

These test development tools can be used in powerful combinations to match the DUT's test flow and test requirements.

Soft Front Panel (SFP)

The SFP assists the user in the development and application of test patterns, allows the user to change key test execution parameters, and allows the user to validate and compensate for test fixture connectivity. During pattern development, the user interactively loads and execute STIL, XML, or bulk data files. When loading, the tests are checked for correct syntax and the SFP generates error messages to help debug patterns. The SFP enables the user to the control various execution and response logging modes. In addition to these features, the SFP uses the same IVI interface driver calls. Each function initiated by the SFP logs an example driver call that can then be used in a regular API environment.





IVI and LabVIEW drivers

The IVI driver set can be used to fully control all aspects of test development using the DSR from assigning hardware pins to creating and executing waveform patterns using the M9195A. The drivers include high level commands for:

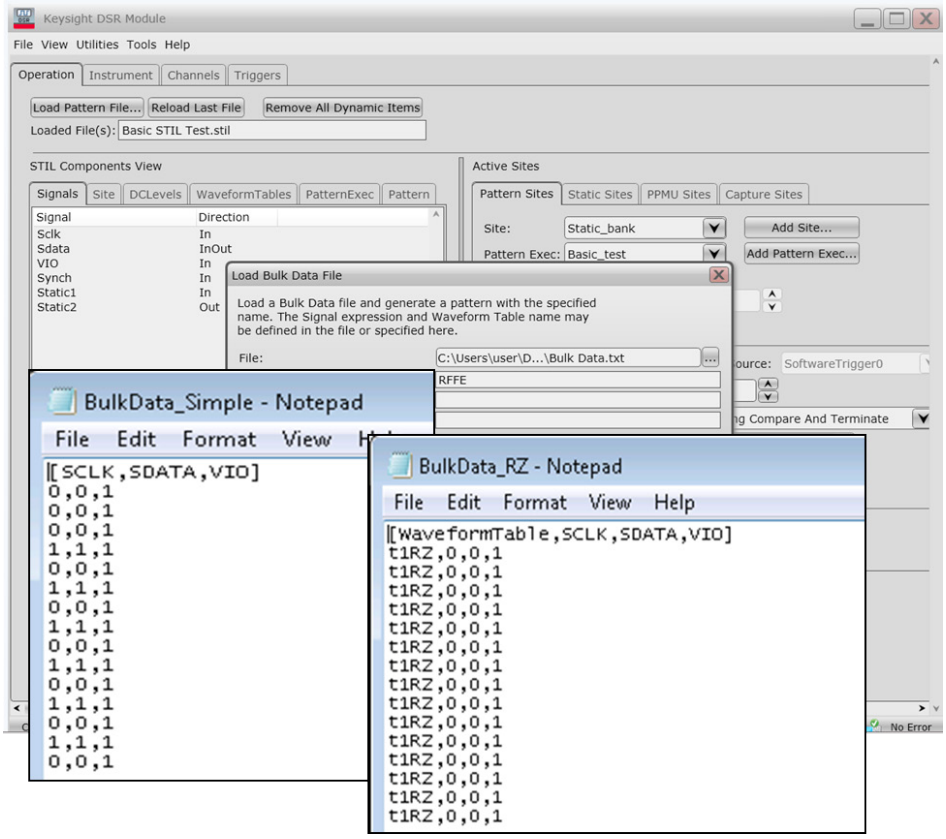
- Initial configuration including pin/channel names assignments, signal direction, grouping pins/channels to make vector definition easier.
- Setting physical layer conditions such as voltage levels, active loads
- Defining single or multisite configurations.
- Pattern definition and waveform timing.
- Pattern sequencing

Standard Test Interface Language (STIL) Support

The PXI DSR takes advantage of the Standard Test Interface language (STIL) IEEE Std 1450.0 which was designed for ATE testing. The PXI DSR can be configured using STIL commands that specify signal grouping, patterns, format, and timing information used to apply digital test vectors to a device being tested. Using a simple text editor and using the STIL format, attributes needed to generate digital patterns can quickly be created. STIL tests are easy to read and understand which simplifies test development and de-bug. Either the IVI API or the SFP can execute tests developed in STIL.

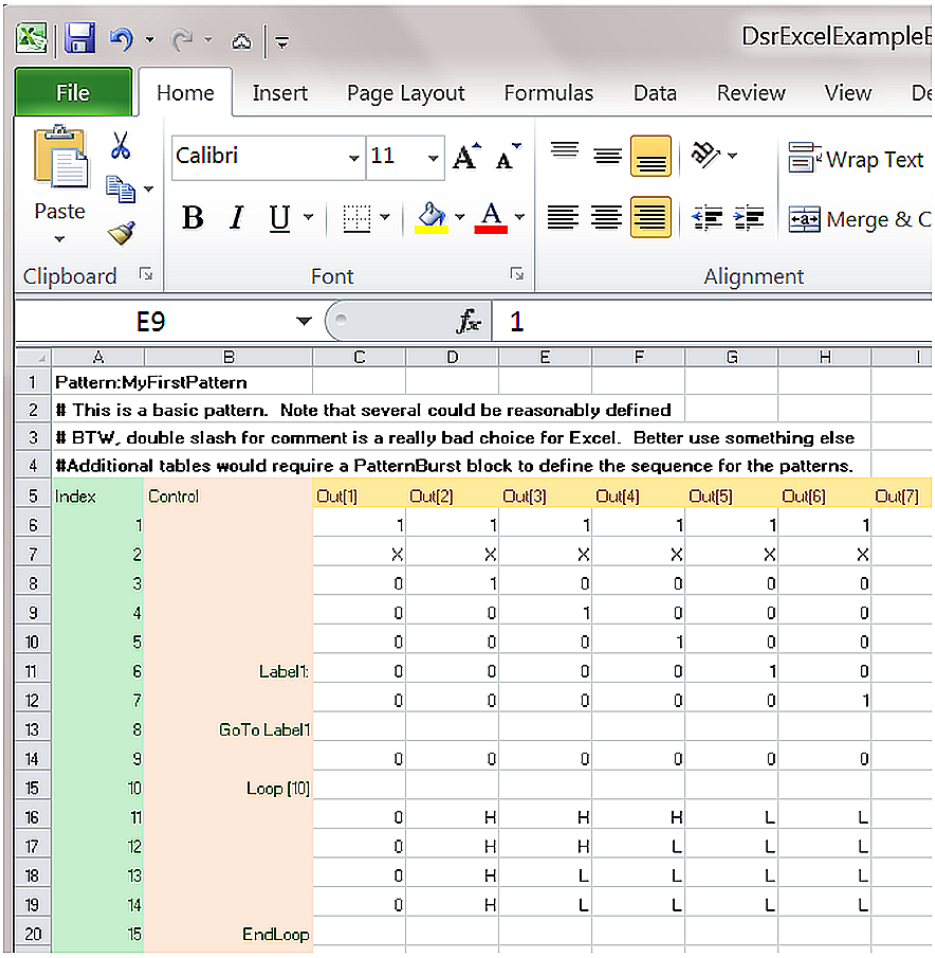
Bulk Data Import

The PXI DSR supports bulk data file import to load legacy and tool generated patterns. Bulk data import utilizes simple text files where the first row contains signal names and provides the option to a reference a waveform table. Each subsequent row represents the vectors which make up the patterns. The waveform table itself can be defined using the SFP, IVI driver, or STIL file. This provides a quick and easy way to develop production tests using patterns developed in R&D.



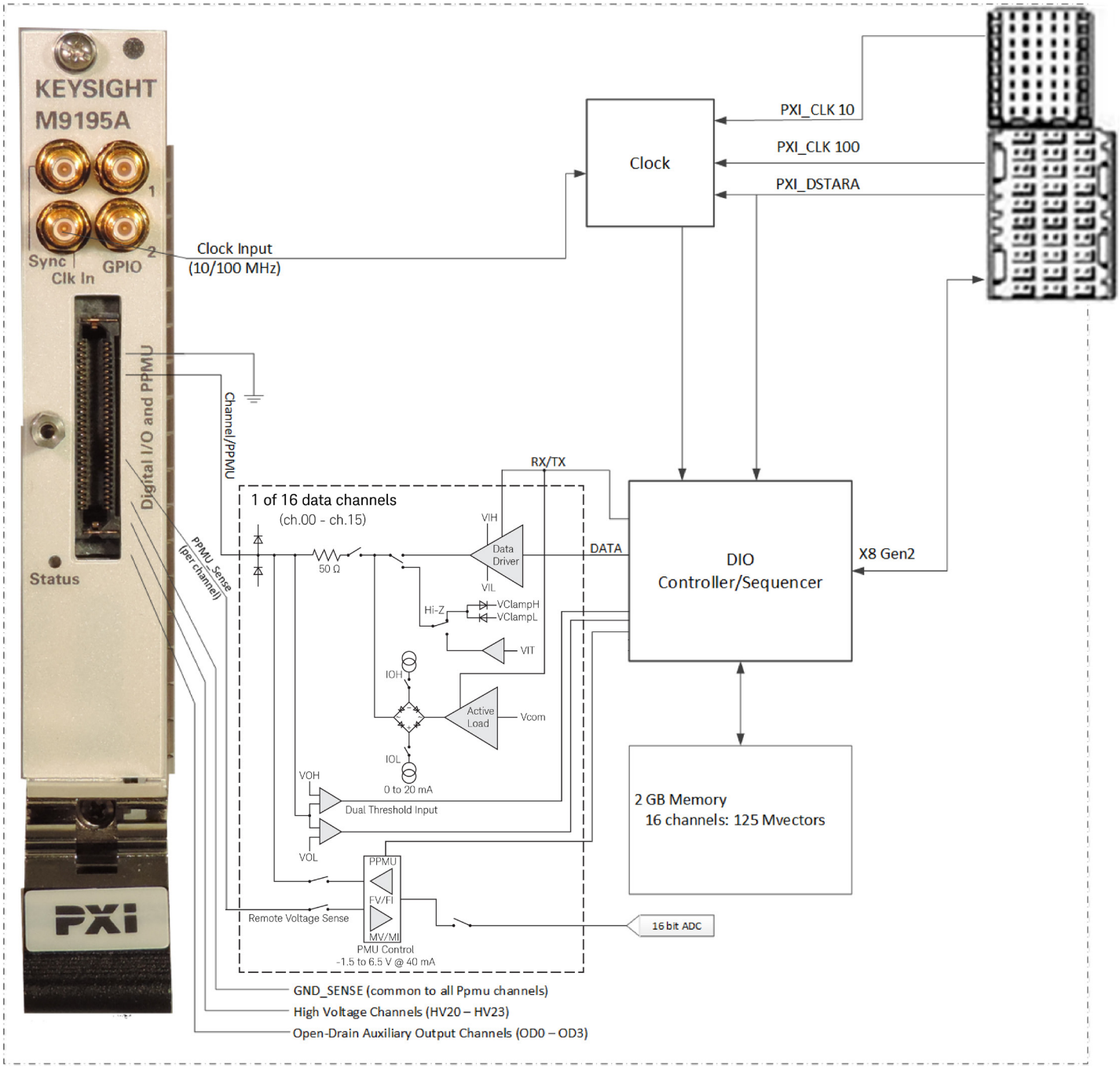
XML (.xlsx) programming interface

The XML interface allows the user to develop and debug tests in a spreadsheet form. The STIL methodology fits well with the multiple worksheet concepts provided in modern spreadsheet tools. Each worksheet matches a STIL function such as Signals, Waveform Tables, and Patterns. Digital patterns are tabular in nature and therefore fit very well into a spreadsheet. The spreadsheet provides an easy to use, flexible, and familiar interface for novice or expert users to quickly develop digital tests. All of the standard spreadsheet tools, such as equations, are available to help with pattern creation. This spreadsheet interface can be used to configure and control the M9195A channels and key features is provided as a standard development tool. Spreadsheet tests can be executed using either the SFP or associated IVI commands.



	A	B	C	D	E	F	G	H	I
1	Pattern:MyFirstPattern								
2	# This is a basic pattern. Note that several could be reasonably defined								
3	# BTW, double slash for comment is a really bad choice for Excel. Better use something else								
4	#Additional tables would require a PatternBurst block to define the sequence for the patterns.								
5	Index	Control	Out[1]	Out[2]	Out[3]	Out[4]	Out[5]	Out[6]	Out[7]
6	1		1	1	1	1	1	1	
7	2		X	X	X	X	X	X	
8	3		0	1	0	0	0	0	
9	4		0	0	1	0	0	0	
10	5		0	0	0	1	0	0	
11	6	Label1:	0	0	0	0	1	0	
12	7		0	0	0	0	0	1	
13	8	GoTo Label1							
14	9		0	0	0	0	0	0	
15	10	Loop [10]							
16	11		0	H	H	H	L	L	
17	12		0	H	H	L	L	L	
18	13		0	H	L	L	L	L	
19	14		0	H	L	L	L	L	
20	15	EndLoop							

Simplified block diagram



Accessories and cables are designed for easy, accurate, and reliable digital IO connections

Single-site (16 channels) signal cables

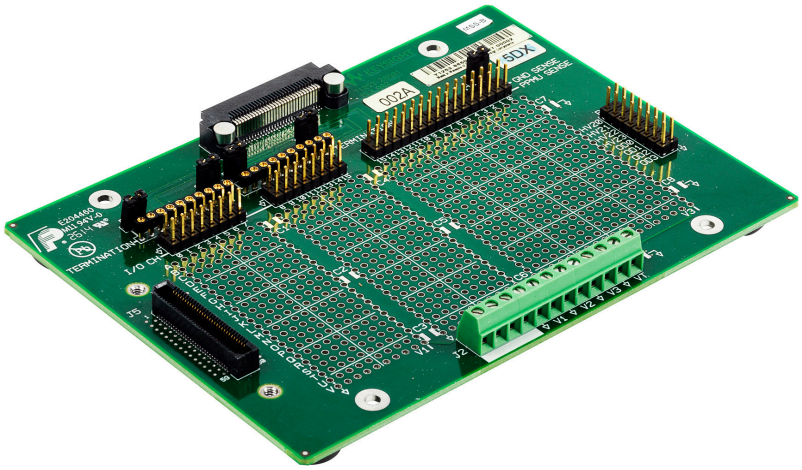
- Y1245A (0.5 meter), Y1246A (1 meter), or Y1247A (2 meter)
- 60 micro coax lines for 16 digital Ch, 16 PMU sense Ch, 4 high voltage Ch , and 4 open drain/grounds Ch
- Male Edge Rate with squeeze latches or thumb screw hood

Multi-site (4 sites of 4 channels) signal cables

- 1248A (1 meter) or Y1249A (2 meter)
- 16 Ch divided into 4 independent partitions (connectors)
- Each partition contains an Edge Rate connector with squeeze latch, 4 digital **Ch,** 4 PMU sense Ch, 1 high voltage Ch, and 1 open drain Ch
- 4 alternate thumb screw hoods are also provided for optional use

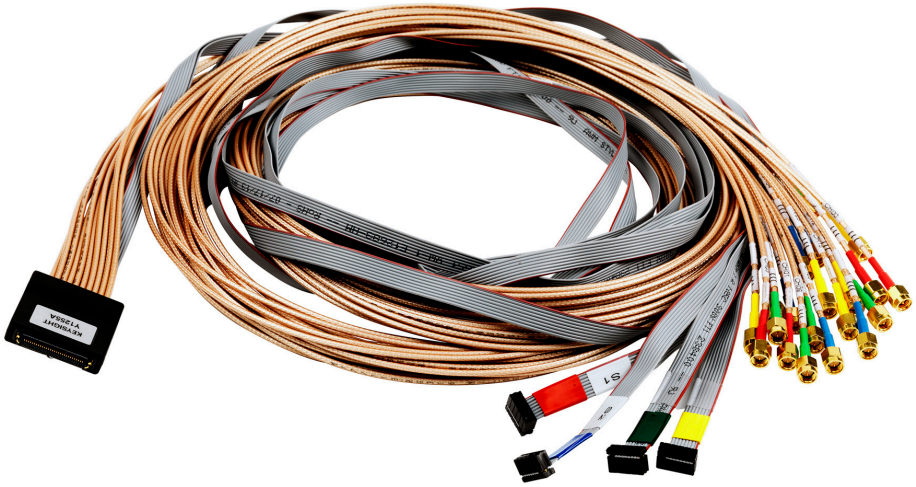
Evaluation and prototyping board

- Y1253A allows users to access individual signal pins for prototyping or debug.
- Board consists of 1 inch of signal header breakout pins, prototyping area with associated power connector, and signal termination pads.
- Offers 9in2 of bread board area, power/ground, includes headers for 16 channels, 16 PMU channels high voltage and open drain channels
- The Y1253A proto board is designed for use with the single-site, Y1245A, Y1246A and Y1247A, cables only.



SMA breakout cables

- Y1254A (1 meter) and Y1255A (2 meter)
- Enables user access to individual signal pins/channels for prototyping or debug
- SMA connectors plus a header for low-speed signals.
- Cables work with both the single and multi-site configurations



Definitions for specifications and characteristics

Specifications	Warranted performance. Specifications include guardbands to account for the expected statistical performance distribution, measurement uncertainties, and changes in performance due to environmental conditions. All specifications and characteristics apply over the operating environment outlined in "Environmental and Regulatory" section of this data sheet. In addition, the following conditions must be met: – Instrument has been turned on for 30 minutes with the PXI DSR software running. – Instrument is within its calibration cycle. – Instrument remains at a stable surrounding environment temperature (between 0°C to 45°C) for 1 hour prior to turn-on. Specifications in this document are identified by an asterisk (*).
Characteristics	A performance parameter that the product is expected to meet before it leaves the factory. A characteristic includes the same guardbands as a specification.
Typical	Expected performance of an average unit at a stable temperature between 20°C to 30°C for 30 minutes prior to turn-on and during operation; does not include guardbands. The instrument must be within its calibration cycle.
Nominal	A general, descriptive term or design parameter. It is not tested. Data represented in this document are nominal unless otherwise identified.
Best practices	To ensure proper cooling, use Keysight slot blockers (Y1212A), filler panels (Y1213A), and the air inlet module kit (Y1214A) in the chassis when there are empty slots. Keysight chassis and filler panels optimize module temperature performance. At environmental temperatures > 40 °C, chassis fans should be set to high.
Additional information	All data are measured from multiple units at room temperature and are representative of product performance within the operating temperature range unless otherwise noted. The specifications contained in this document are subject to change.

Technical specifications and characteristics

General Characteristics	
Module characteristics	
Bus interface & compatibility	PXI Express peripheral module (x1, x4, x8 PCIe® specification v 2.1)
Number of data channels	16, per-channel parametric measurement unit (PPMU)
Number of sites per module	One 16 channel or four 4-channel sites
Maximum data rate for data channels	250 Mbps
Maximum RTZ clock on data channels	250 MHz
Number of high voltage channels	4
Number of auxiliary open drain channels	4
Number of GPIO channels	2 [1]
Module memory	2 GB (allocated between pattern, response capture and sequence control)
Front panel connectors	
Data , open drain, HV, PPMU sense	ERCD30
Reference clock input (REF CLK IN)	SMB connector
Sync in/out (SYNC)	SMB connector [1]
GPIO 1 and GPIO 2	SMB connector [1]
Mechanical characteristics	
Dimensions (H x W x D) in mm	3U/1-slot PXIe standard 130.1 x 21.7 x 210 mm; includes connector and handle extensions
Weight	482 g

1. Reserved for future use.

Technical specifications and characteristics

DC Power Requirements		
DC supply	**Typical**	**Maximum**
DC supply current:		
+3.3 V	3.0 A	4.5 A
+12 V	2.8 A	3.2 A
Power dissipation (max)	44 W	53 W

Data Channel Characteristics		
Characteristic *** denotes warranted specification**	**Value**	**Comments**
Number of data channels	16	
Maximum pattern memory	125 Mvectors per channel	
Channel type	Single-ended, ground reference	
Channel impedence	50 Ω	Nominal
Direction control (In, Out, In/Out)	Per channel, per cycle (period)	
Per cycle digital states	2 drive states, 1 receive state	
Programmable drive states	Force high, force low, force terminate	Terminate state either drives active termination or is high-Z with reflection clamps
Programmable receive states	Compare high, compare low, compare three-state, compare off	Three-state: a signal level between receive high and receive low thresholds
Programmable voltage setting	Per channel	
Drive/receive voltage range	-1.5 V to +6.5 V (16-bit with 152 µV resolution)	VIH – VIL ≥ 100 mV VIL (-1.5 V to +6.4 V) VIH (-1.4 V to +6.5 V)
Drive voltage accuracy *	±25 mV (VIH & VIL) DUT centric	Maximum accuracy from ±5 ° C of AutoCorrections
Receive voltage accuracy *	±20 mV (VOH & VOL) DUT centric	Hysteresis off. Maximum accuracy from ±5 ° C of AutoCorrections
Channel output short circuit current limit	±75 mA, nominal	Maximum of 250 mA per module in combination with other channels
Channel rise time	<450 ps @ 1 V pp (programmed) <700 ps @ 3 V pp (programmed) <1250 ps @ 6 V pp (programmed)	Into 50 Ω, 20-80%, typical
Channel fall time	<450 ps @ 1 V pp (programmed) <700 ps @ 3 V pp (programmed) <1250 ps @ 6 V pp (programmed)	Into 50 Ω, 20-80%, typical
Minimum detectable voltage swing, receive	40 mV	Nominal. Hysteresis off
High impedance leakage, receive	±2 µA	Nominal. Static or dynamic digital mode
Channel power-on state	high-Z	
Receive hysteresis settings	0 mV, 50 mV, 100 mV	
Channel jitter	<25 ps RMS	Typical. EPR* = 1 ns
Channel to channel jitter	<25 ps RMS	Typical. EPR* = 1 ns

*EPR = Edge Placement Resolution

Technical specifications and characteristics

Data Channel Characteristics Characteristic * denotes warranted specification	Value	Comments
Active termination range	-1.5 V to +6.5 V (16-bit with 152 µV resolution)	50 Ω terminated into VIT
Active termination accuracy *	±25 mV (VIT)	Maximum accuracy from ±5 ° C of AutoCorrections
Reflection clamp range	-2 V to +7 V (16-bit with 152 µV resolution)	VCH – VCL > 0.8 V VCL (-2 V to +6.2 V) VCH (-1.2 V to +7 V)
Reflection clamp accuracy	±30 mV @ 1 mA (VCH & VCL) ±200 mV @ 10 mA (VCH & VCL) ±400 mV @ 25 mA (VCH & VCL)	50 Ω source impedence into clamps. Characteristic accuracy from ±5 ° C of AutoCorrections neglecting source impedence voltage drop
Active load range (IOH & IOL)	0 mA to 25 mA (16-bit with 762 nA resolution)	Maximum of 250 mA per module in combination with other channels
Active load accuracy	±0.40 mA (IOH & IOL)	Characteristic accuracy from ±5 ° C of AutoCorrections
Commutation voltage range	-1.5 V to +6.5 V -1 V to +5.5 V	| IOL & IOH | ≤ 1 mA | IOL & IOH | ≤ 25 mA
Commutation voltage accuracy	±20 mV (VCOM)	Characteristic accuracy from ±5 ° C of AutoCorrections

High Voltage Channel Characteristics Characteristic * denotes warranted specification	Value	Comments
Number of high voltage channels	4	
Channel type	Single-ended, ground referenced	
Channel control	Shared with dependent data channel	Refer to user manual for HV control information HV20 shared with CH 02 HV21 shared with CH 06 HV23 shared with CH 10 HV24 shared with CH 14
Channel impedence	<10 Ω (when forcing to terminate) 50 Ω (when forcing High or Low)	Nominal
Channel power-on state	Passive 50 Ω termination	
Maximum data rate	10 MHz	
Programmable voltage range setting	Per channel	
HV drive range	0 V to +13.5 V (16-bit with 305 µV resolution)	Force terminate
HV drive accuracy *	±40 mV (VHH)	Maximum accuracy from ±5 ° C of AutoCorrections
Drive voltage range	-0.1 V to +6.5 V (16-bit with 152 µV resolution)	Force high or low
Drive voltage accuracy *	±35 mV (VIH & VIL)	Maximum accuracy from ±5 ° C of AutoCorrections
HV drive settling time	< 4 µs @ 13.5 V pp into 1 M Ω (1nF) < 350 µs @ 13.5 V pp into 1 M Ω (1nF)	Settled to 1% of final value Typical
HV channel short circuit current limit	±60 mA, nominal	Maximum of 250 mA per module in combination with other channels. Nominal

Technical specifications and characteristics

High Voltage Channel Characteristics Characteristic * denotes warranted specification	Value	Comments
Drive rise time	<9 ps @ 1 V pp (programmed) <10 ps @ 3 V pp (programmed) <11 ps @ 6 V pp (programmed)	Into 50 Ω, 20-80%, Typical
Drive fall time	<9 ps @ 1 V pp (programmed) <10 ps @ 3 V pp (programmed) <11 ps @ 6 V pp (programmed)	Into 50 Ω, 20-80%, Typical
Drive source/sink current per channel	±60 mA, nominal	Maximum of 250 mA per module in combination with other channels

Open Drain Channel Characteristics Characteristic	Value	Comments
Number of auxiliary open drain channels	4	
Channel type	Output only, single-ended, ground referenced	
Channel termination	Open drain	Internal 10k Ω pull-up to +5 V
Sink current per channel	1 A max	Nominal
Channel power-on state	Off	10k Ω pull-up to +5 V
Maximum working voltage	+ 12 Vdc	

Technical specifications and characteristics

PPMU Characteristics **Characteristic** *** denotes warranted specification**	**Value**	**Comments**
Number of PPMU channels	16	
PPMU modes	Force V measure V, Force V measure I, Force I measure I, Force I measure V, Force nothing measure V	
Measurement averaging modes	None, 64 averages, 50 Hz one PLC, 60 Hz one PLC	
Force voltage range	-2 V to +6.5 V (| Current | ≤ 4 mA) -2 V to +6 V (| Current | ≤ 25 mA) -2 V to +5.75 V (| Current | ≤ 40 mA) (16-bit with 152 µV resolution)	
Force voltage accuracy *	± 10mV	Maximum accuracy from ±5 ° C of AutoCorrections. Ground sense tied to ground.
Measure voltage accuracy *	± 10mV	With remote sense. Maximum accuracy from ±5 ° C of AutoCorrections with one PLC averaging at sense location. Ground sense tied to ground
Force voltage settling time	< 20 µS (40 mA range) < 20 µS (1 mA range) < 25 µS (100 µA range) < 100 µS (10 µA range) < 525 µS (2 µA range)	1 V rising and falling step settled to 1% of final value into 1M Ω/ 1nF load. Typical
Force voltage stability	Stable at all ranges into 1 µF	Larger load capacitance possible, but response limited by current slew rate.
Current range	-40 mA to + 40 mA (16-bit with 2.44 µA resolution)	Maximum of 250 mA per module in combination with other channels
	-1 mA to + 1 mA (16-bit with 61 nA resolution)	
	-100 µA to + 100 µA (16-bit with 6.1 nA resolution)	
	-10 µA to + 10 µA (16-bit with 610 pA resolution)	
	-2 µA to + 2 µA (16-bit with 122 pA resolution)	
Force current accuracy *	± 1% of range	Maximum accuracy from ±5 ° C of AutoCorrections. Remote sense disconnected.
Measure current accuracy *	± 1% of range	Maximum accuracy from ±5 ° C of AutoCorrections with one PLC averaging. Remote sense disconnected.
Force current settling time	Dependent on load	
Channel leakage	± 10 nA	Typical
Remote sense	16 channels 1 GND	Ground sense should be tied to ground at measurement location for maximum accuracy.
Remote sense leakage	± 4 nA	Typical
Force current voltage clamp range	-2 V to +6.5 V (16-bit with 152 µV resolution)	VCH > VCL VCL (-2 V to +4 V) VCH (0 V to +6.5 V)
Force current voltage clamp accuracy	± 50 mV	Characteristic accuracy from ±5 ° C of AutoCorrections

Technical specifications and characteristics

Timing and Trigger Specifications and Characteristics		
Channel clock		
Number of independent clock domains	1 - when configured as a single, 16 channel site 4 - when configured as 4, 4 channel sites	Number of independent clocks depends on the number of sites selected
Maximum RZ clock rate on a data channel	250 MHz	
Minimum RZ clock rate on a data channel	5 mHz	
Clock jitter	<25 ps RMS	
Internal reference clock		
Frequency	100 MHz	
Accuracy	±25 ppm	
Period jitter	<2 ps RMS	
Reference clock sources	PXI_CLK100, PXIe-DSTARA, CLK IN	
External reference clock input (SMB front panel)		
Input frequency	10 MHz or 100 MHz	
Input impedance (CLK IN)	50 Ω	Nominal, AC coupled
Input voltage range (CLK IN)	+1.8 V to + 3.3 V	
Lock range accuracy	±25 ppm	
Duty cycle	40 to 60%	
Channel timing (per channel)		
Waveform timing change	Per vector	
Edge placement resolution (EPR)	1 ns minimum	Dependent on waveform table period
Stimulus delay resolution per test: – For EPR £ 1 ns and ≤ 1.3 ns – For EPR > 1.3 ns	 24 ps EPR	Edge Placement Resolution (EPR) is specified at the time of test activation.
Stimulus delay range per test	254 x EPR	
Response delay compensation resolution per test: – For EPR £ 1 ns and ≤ 1.3 ns – For EPR > 1.3 ns	 24 ps EPR	Edge Placement Resolution (EPR) is specified at the time of test activation.
Response delay compensation range per test	254 x EPR	
Channel-to-channel skew	±300 ps	At 1ns EPR
Trigger characteristics		
Trigger sources	Software (API-driven)	
Waveform characteristics		
Number of waveform tables	32	
Number of waveform characters	15 (user definable)	
Generation waveform iteration count	Once, n times, infinite	
Receive post trigger sampling	0 to full record waveform	

Technical specifications and characteristics

Environmental Characteristics		
Operating and storage conditions	**Operating**	**Storage**
Temperature	0 to 45 °C	-40 to +70 °C
Humidity	Maximum 80% at 40°C (non-condensing)	
Altitude	3,000 meters, de-rate max temperature by 5 °C above 2,000 meters	
Calibration interval	1 year: return to Keysight service center or use Y1252A with N7800A/N7867A	
Mechanical		
Operating vibration	5-500 Hz: 0.21 g RMS, random	
Survival sine vibration	5-500 Hz: 0.5 g (0 to peak), swept sine	
Survival random vibration	5-500 Hz: 2.09 g RMS, random	
Transportation shock	125 G, 8.6 m/s, trapezoidal pulse	
End use handling shock	1.6 m/s, <3 msec duration, half-sine pulse	
Warm-up time	30 minutes	

Samples of this product have been type tested in accordance with the Keysight environmental test manual and verified to be robust against the environmental stresses of storage, transportation and end-use; those stresses include but are not limited to temperature, humidity, shock, vibration, altitude, and power line conditions. Test methods are aligned with IEC 60068-2 and levels are similar to MIL-PRF-28800F Class3.

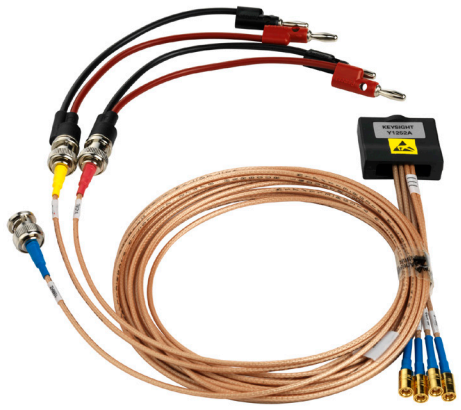
Regulatory
Safety
IEC/ EN 61010-1 USA: ANSI/UL 61010
EMC
IEC 61326-1

Module Calibration

Both adjustment and performance verification is required to calibrate M9195A modules. Self-maintainers can perform these procedures by using software available from Keysight:

- N7800A Test management environment
- N7876A PXI digital IO calibration application

Module adjustment requires the Y1252A adjustment cable. This accessory consists of three cable assemblies necessary for voltage and current adjustments of the M9195A. These cables are used with a high-end digital multimeter (DMM) to adjust on-board analog-digital conversion. The N7876A is required to make adjustments using this cable.



Other instruments and hardware is required for calibration. The N7876A WebHelp file lists the equipment required for adjustment and verification of the M9195A when using the N7800A and N7876A. For more details and access to the N7876A WebHelp file see: http://cal.software.keysight.com/.

Software information

Supported operating systems	Microsoft Windows 7 (32/64-bit)
Standard compliant drivers	IVI-COM, IVI-C, MATLAB
Supported application development environments (ADE)	VisualStudio (VB.NET, C#, C/C++), VEE, LabVIEW, LabWindows/CVI, MATLAB
Keysight IO libraries (version 16.3 update 2 or newer)	Includes: VISA libraries, Keysight Connection Expert, IO monitor
Keysight command expert	Instrument control for SCPI or IVI-COM drivers

Ordering information

Model	Description
M9195A	**PXIe Digital Stimulus/Response with PPMU: 250 MHz, 16 Ch**
M9195A-M12	Memory, 125 Mb/channel
M9195A-S04	Multi-site configuration
M9195A-SR2	Maximum clock rate, 250 MHz
Accessories and cables	
Y1245A	Single-site DSR cable: 0.5 m
Y1246A	Single-site DSR cable: 1m
Y1247A	Single-site DSR cable: 2m
Y1248A	Multi-site DSR cable: 1m
Y1249A	Multi-site DSR cable: 2m
Y1252A	DSR adjustment cable
Y1253A	DSR Evaluation and prototyping board
Y1254A	DSR SMA breakout cable: 1m
Y1255A	DSR SMA breakout cable: 2m

Related products

M9381A PXIe Vector Signal Generator: 1 MHz to 3 GHz or 6 GHz
M9393A PXIe Performance Vector Signal Analyzer: 9 kHz to 27 GHz
M9371A PXIe Vector Network Analyzer, 300 kHz to 6.5 GHz
M9300A PXIe Frequency Reference: 10 MHz and 100 MHz
M9018A PXIe 18-Slot Chassis
M9037A PXIe High Performance Embedded Controller

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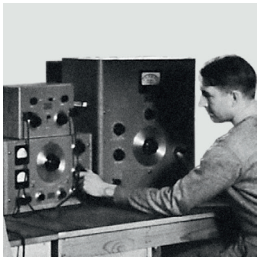

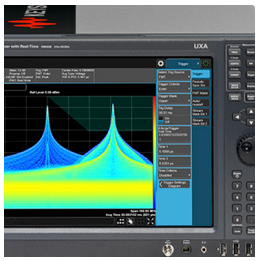

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